

**Search Notes**

Application/Control No.

10/574,933

Examiner

Tuan Quach

Applicant(s)/Patent under  
Reexamination

NAKAYAMA ET AL.

Art Unit

2826

**SEARCHED**

Class	Subclass	Date	Examiner
257	734, 765, 768-771	3/4/2007	TQ
438	656, 660	3/4/2007	TQ
438	686	3/4/2007	TQ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT; USPGPUB; EPO; JPO; DERWENT; IBMTDB) see search history printout	3/4/2007	TQ